Search Notes		

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10/734,221

Examiner

Stephen J. Stein

Applicant(s)/Patent under Reexamination

NAGASAWA ET AL.

Art Unit

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	SEARCHED		
Class	Subclass	Date	Examiner
428	698	9/30/2005	sls
428	446	9/30/2005	SJS
117	952	9/30/2005	SJS
117	953	9/30/2005	SJS

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH (INCLUDING SEAI	RCH STRATEGY)
	DATE	EXMR
Inventor Search	9/30/2005	sıs
West Search (USPAT/PGPUBS) (Derwent/EPO/JPO)	9/30/2005	sıs